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U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

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|---|---------------------------|----------------------------------|-----------------|------------------------------|---------------------|
| APPL NUM 10072734 | FILING DATE 02/05/2002 | CLASS 324 | SUBCLASS 754 | GAU 2858 | EXAMINER KARLSEN |
| **APPLICANTS: Hembree David; Farnworth Warren; Akram Salman; Wood Alan; Doherty C; Krivy Andrew; 2829 | | | | | |
| **CONTINUING DATA VERIFIED: THIS APPLICATION IS A DIV OF 09/929.388 08/14/2001 PAT 6.359.456 WHICH IS A DIV OF 09/303.367 04/30/1999 PAT 6.275.052 WHICH IS A DIV OF 08/797.719 02/11/1997 PAT 6.060.891 | | | | | |
| ** FOREIGN APPLICATIONS VERIFIED: | | | | | |
| PG-PUB DO NOT PUBLISH | | RESCIND <input type="checkbox"/> | | | |
| Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials | | | | ATTORNEY DOCKET NO 96-750 | |
| TITLE : Method for testing semiconductor wafers | | | | | |

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| NOTICE OF ALLOWANCE MAILED | | CLAIMS ALLOWED | |
| | | Total Claims Print Claim for O.G | |
| ISSUE FEE | | DRAWING | |
| Amount Due | Date Paid | Sheets Drwg. | Figs.Drwg. |
| | | Print Fig. | |
| <input type="checkbox"/> TERMINAL DISCLAIMER | | Primary Examiner PREPARED FOR ISSUE Application Examiner | |
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